

ATTORNEY DOCKET NO.: D5116-00002

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Saxena et al.

Serial No.: 09/675,427

Examiner: not assigned

Efficient Method for Modeling and Simulation of the Impact of Local and Global

For: Efficient Method for Modeling and Situation
Variation on Integrated Circuits

I CERTIFY THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE U.S. POSTAL SERVICE AS FIRST CLASS MAIL INTAN ENVELOPE ADDRESSED TO THE ASSISTANT COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231

Assistant Commissioner for Patents Washington, D.C. 20231

Dear Sir:

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL LETTER

Enclosed herewith is an Information Disclosure Statement pursuant to 37 CFR. § 1.56 in connection with the above-identified application, which statement is being

filed:

- Together with the present application.
- Before the first Office Action on the merits or three (3) months from the [X] filing date of this application, whichever occurs last. [37 CFR § 1.97(b)]

PATENT

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- [] After the first Office Action on the merits, but before a Final Office Action under §1.113 or Notice of Allowance under §1.311, whichever occurs first. [37 CFR § 1.97(c)]
- After a Final Office Action under §1.113 or Notice of Allowance under §1.311, but prior to or with payment of the Issue Fee. [37 CFR § 1.97(d)]

Consistent with Applicant's obligations pursuant to 37 CFR §§1.97 and 1.98, the following requirements have been met:

- [X] No separate requirements are needed.
- [x] No additional fee is required.
- [] Fee Under 37 CFR § 1.97(c) or 1.97(d)

The fee of \$180.00 for submission of an IDS under § 1.97(c) as set forth in § 1.17(p) accompanies this statement.

[] Certification Under 37 CFR § 1.97(e)

The undersigned certifies:

- [] 1 that each item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or
- [] 2 that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the statement after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in §1.56(c) more than three months prior to the filing of the information disclosure statement.

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Provision of Copies of References

[x]	A copy of each of the references listed on the attached Form PTO-1449 is
	enclosed herewith and forms a part hereof.

- [] A translation of Reference__ is enclosed herewith and forms a part hereof.
- [] A copy of the European Search Report from a corresponding or related EPO application is enclosed herewith.
- [] A copy of the International Search Report from a corresponding or related PCT application is enclosed herewith.

Identification of Prior Application(s) In Which Listed Information Was Already Cited And For Which No Copies Are Submitted Or Need Be Submitted

- [] This application relies, under 35 U.S.C. § 120, on the earlier filing date of prior U.S. Application No(s). , filed . The following references were submitted to, and/or cited by, the Office in the prior application(s) and therefore are not required to be provided in this application:
- [X] The Commissioner is hereby authorized to charge any fees associated with this communication or credit any overpayment to Deposit Account No. <u>04-1679</u>. A duplicate copy of this transmittal is attached.

Respectfully submitted,

Date: October 2, 2001

Registration No. 37,163

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Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office			Docket No. D5116-00002			Serial No. 09/675,427			
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	B Nurani et al., "In-Line Yield Prediction Methodologies Using Patterned Wafer Inspection Information", IEEE Transactions on Semiconductor Manufacturing, Vol. 11, No. 1, Feb 1998, pp.40-47								
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